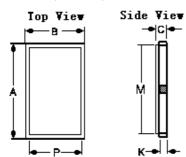
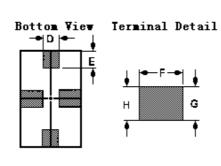
### 1.Package Dimension

(SM-2)





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G

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	Millimeters				
		Max			
А		6.30			
В		4.44			
С		2.08			
D	0.94	1.10			
Е	0.83	1.20			
F	1.16	1.53			
G	0.94	1.10			
Н	0.43	0.59			
K	1.96	2.00			
М		4.8			
Р		2.9			

## 2.Marking

# NDR433.42S2

2-1.Colour: Black

2-2.Center Frequency(MHz):433.42

### NDR433.42S2

# **NEDI** 3.Performance

#### 3-1.Maximum Rating

DC Voltage V <sub>DC</sub>	30V
AC Voltage V <sub>PP</sub>	10V(50Hz/60Hz)
Operation Temperature	-40°C to +85°C
Storage Temperature	-40°C to +85°C
RF Power Dissipation	0 dBm

#### **3-2Electronic Characteristics**

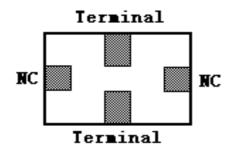
C	haracteristic	Sym	Minimum	Typical	Maximum	Units
Center Frequency (+25°C)	Absolute Frequency	fc	433.345		433.495	MHz
	Tolerance from 433.42 MHz	Δfc		±75		kHz
Insertion Loss				1.3	2.0	dB
Quality Factor	Unloaded Q	$Q_{U}$		12,600		
	50 Ω Loaded Q	$Q_L$		2,000		
Temperature Stability	Turnover Temperature	T <sub>0</sub>	24	39	54	°C
	Turnover Frequency	$f_0$		fc+2.7		kHz
	Frequency Temperature	FTC		0.037		ppm/°C
Frequency Aging	Absolute Value during the First Year	fA		≤10		ppm/yr
DC Insulation Resistance between Any Two Pins			1.0			MΩ
RF Equivalent RLC Model	Motional Resistance	R <sub>M</sub>		12	26	Ω
	Motional Inductance	L <sub>M</sub>		79.1546		μH
	Motional Capacitance	См		1.6854		fF
	Pin 1 to Pin 2 Static	Co		2.3		pF

# CAUTION: Electrostatic Sensitive Device. Observe precautions for handling NOTES:

- 1. Frequency aging is the change in  $f_c$  with time and is specified at +65°C or less. Aging may exceed the specification for prolonged temperatures above +65°C. Typically, aging is greatest the first year after manufacture, decreasing in subsequent years.
- 2. The frequency  $f_c$  is the frequency of minimum IL with the resonator in the specified test fixture in a 50  $\Omega$  test system with VSWR  $\leq 1.2$ : 1. Typically,  $f_{\text{oscillator}}$  or  $f_{\text{transmitter}}$  is less than the resonator  $f_c$ .
- 3. Typically, equipment utilizing this device requires emissions testing and government approval, which is the responsibility of the equipment manufacturer.
- 4. Unless noted otherwise , case temperature  $T_c{=}{+}25\,^\circ\!\mathrm{C}{\pm}2\,^\circ\!\mathrm{C}{.}$
- 5. The design, manufacturing process, and specifications of this device are subject to change without notice.
- 6.Derived mathematically from one or more of the following directly measured parameters:  $f_c$ , IL, 3 dB bandwidth,  $f_c$  versus  $T_c$ , and  $C_0$ .
- 7. Turnover temperature,  $T_0$ , is the temperature of maximum (or turnover) frequency,  $f_0$ , The nominal center frequency at any case temperature, TC, may be calculated from :  $f = f_0 [1-FTC (T_0-T_c)^2]$ . Typically, oscillator  $T_0$  is 20° less than the specified resonator  $T_0$ . 8. This equivalent RLC model approximates resonator performance near the resonant frequency and is provided for reference
- 8. This equivalent RLC model approximates resonator performance near the resonant frequency and is provided for reference only . The capacitance  $C_0$  is the measured static (nonmotional) capacitance between either pin 1 and ground or pin 2 and ground . The measurement includes case parasitic capacitance



4. Electrical Connections



5. Typical Test Circuit

